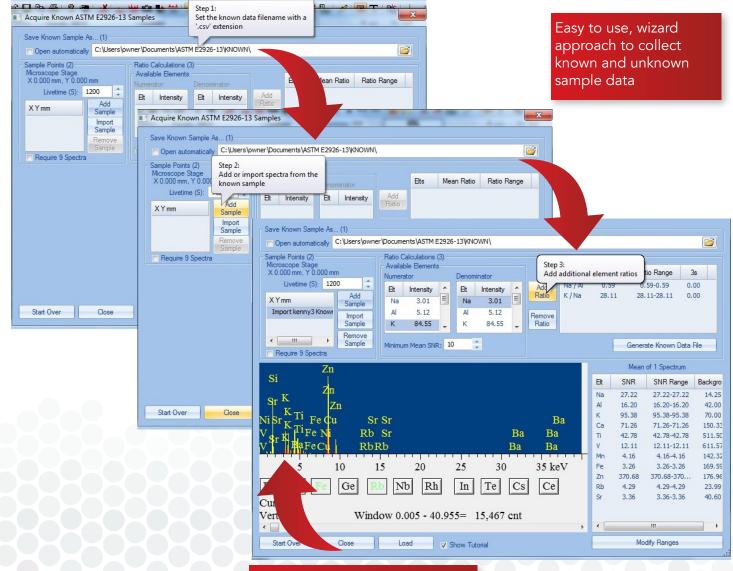
IXRF Systems is proud to present the addition of the "ASTM Method for Forensic Comparison of Glass Using Micro X-ray Fluorescence (µ-XRF) Spectrometry"

to our software, Iridium Ultra.

The ASTM method is for the non-destructive comparison of forensic glass fragments by determining the major, minor, and trace elements present in the glass. Iridium Ultra incorporates all of the analytical requirements of the ASTM method in an easy to use format, that includes everything from automatic peak identification to automatic report generation. The guidelines of the method are built into the software to assure that all aspects of the method are correctly followed and documented.

Spectra can be collected via IXRF's Micro-XRF mounted on an SEM or by importing spectra collected from a benchtop XRF.



Automatic Peak Identification



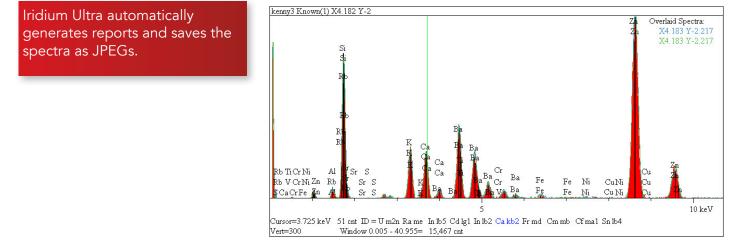


ASTM E2926-13

Forensic Comparison of Glass

using Micro X-ray Fluorescence (µ-XRF) Spectrometry

Unknown samples can be automatically searched against a saved library of known samples, in-house standards, or certified reference standards.



-21	A	В	С	D	E	F	G	Н	1	J	К	L	M
1	ASTM E2926-13 report for Question Sample "kenny3"												
2	Generated 12/6/2013 by iXRF Iridium Ultra Software												
3													
4	Q = Ques	tioned											
5													
6	Spectrur	spectrum overlay shown in files:											
7		C:\Documents and Settings\Administrator\Documents\ASTM E2926-13\REPORT\kenny3.jpg											
8	C:\Documents and Settings\Administrator\Documents\ASTM E2926-13\KNOWN\Known kenny								n kenny3	jpg			
9													
10	Summary Table of Analysis Results:												
11		Known	Element		Ca / K	Ca / AI							
12		Known k	Yes	Range O	Range O	Range O	verlap						
13													
14	Decision												
15		Element											
16		(Q) kenn		AI	К	Ca	Ti	V	Mn	Fe	Zn		
17											361.29-381.91		
18		SNR Mea		14.75	81.33	76.81	38.53	15.22	5.33	4.15	371.9		
19		Backgrou	10.29	38.63	79.33	133.02	565	581.43	120.71	167.11	175.24		
20											-		
21	-	Known k		AI	К	Ca	Ti	V	Mn	Fe	Zn	Sr	Y
22				16.20-20.									
23	-	SNR Mea		18.86	85.96	80.17	39.29	13.79	3.32	5.31	366.41	4.59	4.18
24	-	Backgrou	11.88	35	75.33	128.92	557	596.86	145.14	152.82	183.85	36.87	20.32
25 26	-	Detie Te	h la n										
26		Ratio Tables: (Q) kenn Ca / Ti Ca / K		Ca / Al									
27				0.00-68.6									
28	-	Katlo Ra	0.00-1.04	0.00-68.0	0.00-7.95								
30	-	Known k	() / Ti	Ca / K	Ca / Al								
31				0.00-0.01									
32	-	Natio Ka	0.00-0.01	0.00-0.01	0.02-0.11								

Iridium Ultra automatically calculates element ratios and signal to noise ratios per ASTM method.

In addition, it automatically creates Excel Spread Sheets.

Want More information?

Contact us at sales@ixrfsystems.com or +1 512.386.6100

1	A	В	С	D	E	F	G	Н
1	Known ke	enny3 gen	erated 12/	6/2013 Бу	iXRF Iridiu	m Ultra So	oftware	
2								
3	Ratio table:		1					
4	Ratio	Mean	Low	High	3s		8	
5	Ca/Ti	0.01	0	0.01	0.01			
6	Ca/K	0	0	0.01	0.01			
7	Ca/Al	0.06	0.02	0.11	0.11			
8							8	
9	Element	table						
10			SNRLow	SNR Hial	Mean Ba	ekaround		
11	Na	26.09	21.13	29.92	11.88			
12	AL	18.86	16.2	20.89	35			
13	ĸ	85.96	71.42	95.38	75.33			
14	Ca	80.17	69.18	100.07	128.92			
15	Ti	39.29	35.83	42.78	557			
16	V	13.79	12.11	15.8	596.86		8 8	
17	Mo	3.32	2.74	4.16	145.14			
18	Fe	5.31	3.26	8.48	152.82			
19	Zn	366.41	337.21	391.33	183.85			
20	Sr	4.59	3.16	7.24	36.87			
21	Y	4.18	0.10	2.16-12.5				
22		1.10		E. 10 1E. 4	20.02			
23	Ranges table						-	
24			High Pre	Low Pea	High Pes	Low Pos	High Post	-neak
25	Na	0.92	0.96	0.95	1.13	1.12	1.16	peak
26	Mg	1.13	1.17	1.16	1.34	1.33	1.37	
27	Al	1.38	1.42	1.42	1.56	1.55	1.57	
28	S	2.11	2.16	2.21	2.41	2.46	2.51	
29	ĸ	3.19	3.22	3.25	3.4	3.41	3.44	
30	Ca	3.17	3.21	3.49	3.89	4.24	4.28	
31	Ti	4.22	4.31	4.36	4.66	4.24	4.20	
32	v	4.22	4.75	4.30	4.00	5.15	5.2	
33	Cr	5.11	5.21	5.26	5.56	5.61	5.2	
34	Mn	5.59	5.69	5.20	6.04	6.09	6.19	
35	Fe	6.05	6.15	5.74	6.6	6.65	6.75	
36	re Co	6.67	6.72	6.77	7.07	7.12	7.17	
30		7.2						
	Ni 		7.27 kenny3	7.32	7.62	7.67	7.74	